

# ISL28133 Long Term Drift

Figure 2 shows a plot of daily  $V_{OS}$  drift measurements of 30 individual ISL28133 amplifiers over a continuous 572 day period at +25°C. The 30 units were connected in a gain of 10k (see Figure 3), mounted on a single PC board and kept at room temperature. The 30 amplifier outputs were measured daily by a DVM and scanner under computer control. The daily  $V_{OS}$  measurements were subtracted from the initial  $V_{OS}$  value to calculate the  $V_{OS}$  shift from zero-hour. The test board was powered from a UPS to maintain uninterrupted power to the test units. Three instances of lost measurement data ranging from 2 days to 2 weeks due to power loss to the measurement scanner were detected, and data was interpolated.

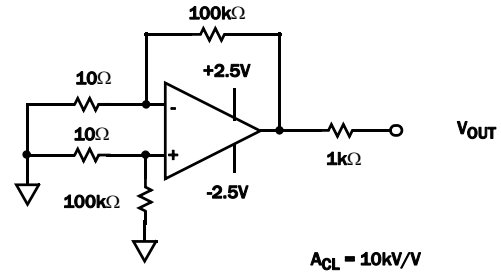


FIGURE 1. LONG TERM DRIFT TEST CIRCUIT

The change in amplifier  $V_{OS}$  over the 572 day period for all 30 amplifiers (see Figure 2) was less than  $\pm 100\text{nV}$ , and no clear  $V_{OS}$  long term drift trend was evident in the data. The excellent long term drift performance is a result of the chopper amplifier's ability to measure and correct  $V_{OS}$  errors, leaving only the  $V_{OS}$  error contribution due to changes in the long term stability of the external components.

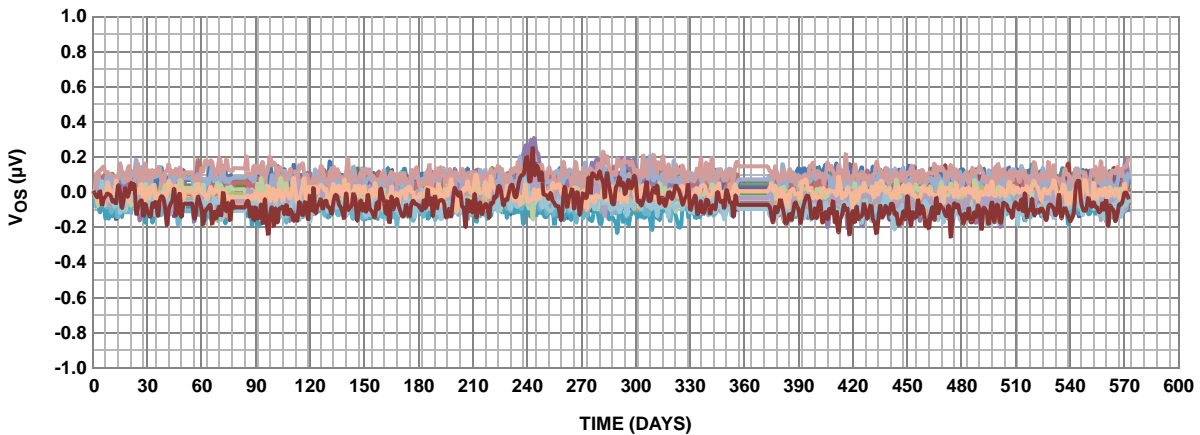


FIGURE 2. LONG TERM DRIFT ( $V_{OS}$  vs TIME) FOR 30 UNITS

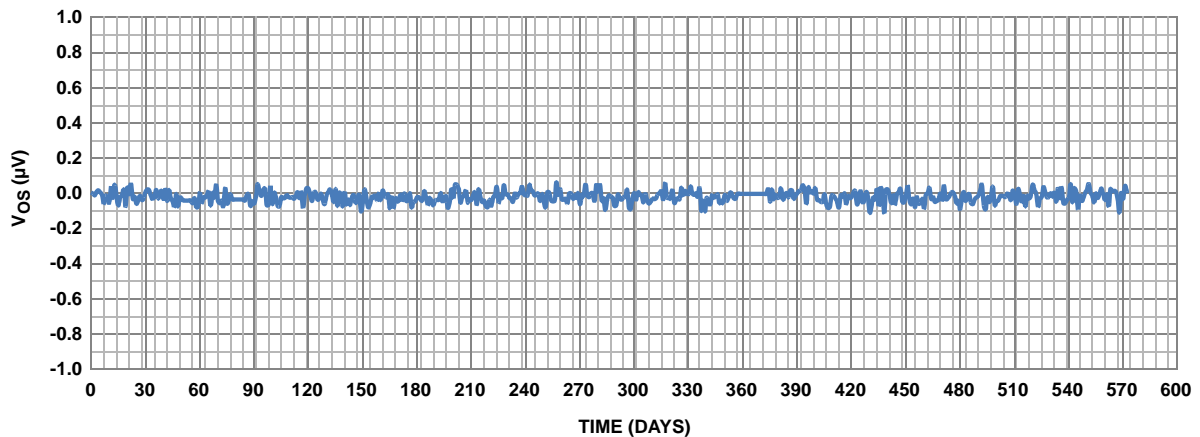


FIGURE 3. LONG TERM DRIFT ( $V_{OS}$  vs TIME) FOR A SINGLE UNIT